



INTERNATIONAL
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CERTIFICATE OF ACCREDITATION

This is to attest

INYMET, S.A. DE C.V.

SALVATIERRA NO. 32-5, COL SAN BARTOLO ATEPEHUACAN
GUSTAVO A MADERO, 07730, MEXICO

Calibration Laboratory CL-101

has met the requirements of AC204, *IAS Accreditation Criteria for Calibration Laboratories*, and has demonstrated compliance with ISO/IEC Standard 17025:2017, *General requirements for the competence of testing and calibration laboratories*. This organization is accredited to provide the services specified in the scope of accreditation.

Expiration Date April 1, 2027

Effective Date February 19, 2025



International Accreditation Service
Issued under the authority of IAS management

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Accredited to ISO/IEC 17025:2017

Effective Date February 19, 2025

CALIBRATION AND MEASUREMENT CAPABILITY (CMC)*

MEASURED QUANTITY or DEVICE TYPE CALIBRATED	RANGE	UNCERTAINTY ^{1,2} (±)	CALIBRATION METHOD OR PROCEDURE, STANDARD EQUIPMENT (OPTIONAL)
<i>Dimensional</i>			
Calipers (Vernier, Dial, Electronic)	Up to 150 mm Up to 300 mm Up to 600 mm Up to 1000 mm	8 µm 10 µm 12 µm 20 µm	Direct Method Gauge blocks
Outside Micrometers	Up to 25 mm Up to 50 mm Up to 300 mm	0.7 µm 0.8 µm 12 µm	Direct Method Gauge blocks
Inside Micrometer	5 mm to 30 mm 50 mm to 300 mm	1 µm 10 µm	Direct Method Gauge blocks & gauge block holder
Depth Micrometer	Up to 100 mm	3.5 µm	Direct Method Gauge blocks
Height Gauges (Vernier & Dial & Electronic)	Up to 600 mm Up to 1000 mm	2 µm 3.5 µm	Direct Method Gauge blocks & Long gauge blocks
Dial Indicators (Plunger Type)	Up to 25 mm 25 to 100 mm	1.0 µm 2.6 µm	Direct Method Electrical comparator with LVDT Probe
Dial Indicator (Lever Type)	Up to 0.2 mm Up to 2 mm	1.7 µm 8 µm	Direct Method Electrical comparator with LVDT Probe
Electrical Comparator (Analog / Digital Display)	Up to 50 mm	1 µm	Direct Method Gauge blocks
Length Bar	Up to 25 mm 25 mm to 50 mm 50 mm to 100 mm 100 mm to 200 mm 200 mm to 500 mm	1 µm 1.5 µm 2 µm 2.5 µm 3.8 µm	Direct Method Gauge blocks & long gauge blocks and electronic comparator with LVDT Probe

* If information in this CMC is presented in non-SI units, the conversion factors stated in NIST Special Publication 811 "Guide for the Use of the International System of Units (SI)" apply.

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MEASURED QUANTITY or DEVICE TYPE CALIBRATED	RANGE	UNCERTAINTY ^{1,2} (±)	CALIBRATION METHOD OR PROCEDURE, STANDARD EQUIPMENT (OPTIONAL)
	500 mm to 1000 mm	2 mm	
Scales, Steel Rules, Steel Tapes	Up to 1 m 1 m to 50 m	0.3 mm (0.5 + 0.02 L) mm Where L is in meters	Direct Method Standard Ruler Standard glass scale & reticles, Vernier Caliper
Feeler Gauges	Up to 1 mm 1 mm to 2 mm	1.2 µm 2 µm	Direct Method Micrometer (digital)
Bevel Protractor	Up to 360°	0.7'	Direct Method Angle Gauges
Surface Plate	1600 mm x 1000 mm	10 µm	Direct Method Using precision level of 0.02 mm/m sensitivity
Dial Thickness Gauge	Up to 25 mm	1 µm	Direct Method Gauge blocks
Mechanical			
Absolute Pressure Gauges	10 kPa to 7 MPa	0.01 %	Direct / Comparison Method Dead Weight Tester (Pressure Balance) & Barometer
Differential Pressure Gauge	0 inH ₂ O to 1 inH ₂ O 1 inH ₂ O to 5 inH ₂ O 5 inH ₂ O to 30 inH ₂ O	0.001 inH ₂ O 0.005 inH ₂ O 0.007 inH ₂ O	Direct / Comparison Method Dead Weight Tester (Pressure Balance) & Barometer
Pressure Gauge	1.24 kPa to 21 kPa 21 kPa to 7000 kPa 7000 kPa to 70 MPa	0.025 % 0.015 % 0.01 %	Direct Method Dead Weight Tester (Pressure Balance)
Vacuum Gauge	0 bar to -1 bar	0.41 mbar	Comparison Method Barometer & Pressure Calibrator
Volume Measurement Equipment	5 µL to 100 µL 100 µL to 5 mL 5 mL to 150 mL 150 mL to 4000 mL 4 L to 20 L 20 L to 500 L	0.05 µL 0.3 µL 15 µL 100 µL 3.2 mL 32 mL	Gravimetric Method Electronic Balance
	20 L to 50 L 50 L to 200 L	4.5 mL 11 mL	Direct Transfer Method Volumetric Standard
	200 L to 5000 L 5000 L to 1,000,000 L	60 mL 6 L	Direct Transfer Method

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MEASURED QUANTITY or DEVICE TYPE CALIBRATED	RANGE	UNCERTAINTY ^{1,2} (±)	CALIBRATION METHOD OR PROCEDURE, STANDARD EQUIPMENT (OPTIONAL)
			Volumetric Standard / Dual Rotor Turbine, Coriolis Meter
Liquid Flow By Total Mass	0.1 kg to 0.4 kg	0.77 %	Gravimetric Method Electronic Balance
	0.4 kg to 20 kg	0.03 %	
	20 kg to 400 kg	0.05 %	
	400 kg to 500 kg	0.10 %	
	2 kg to 5 x 10 ⁶ kg	0.20 %	Against Ref Std. Flowmeter
Liquid Flow By Total Volume	0.1 L to 20 L	0.05 %	Gravimetric Method Electronic Balance
	20 L to 400 L	0.07 %	
	400 L to 500 L	0.12 %	
		2 L to 5 x 10 ⁶ L	
Liquid Flow Rate Mass per Unit Time	0.1 kg/min to 20 kg/min	0.10 %	Gravimetric Method Electronic Balance
	20 kg/min to 400 kg/min	0.12 %	
	400 kg/min to 500 kg/min	0.17 %	
		2 kg/min to 1000 kg/min	
Liquid Flow Rate Volume per Unit Time	0.05 mL/min to 0.150 L/min	1.2 %	Gravimetric Method Electronic Balance
	0.150 mL/min to 20 L/min	0.12 %	
	20 L/min to 400 L/min	0.15 %	
	400 L/min to 1000 L/min	0.20 %	
		2 L/min to 1000 L/min	
Gas Flow By Total Mass	0.1 g to 15 kg	0.20 %	Gravimetric Method Electronic Balance
	0.1 g to 5 x 10 ⁶ kg	0.35 %	Comparison Method Against Ref. Std. Flowmeter
Gas Flow By Total Volume	0.1 L to 1 L	0.82 %	Gravimetric Method Electronic Balance
	1 L to 5000 L	0.25 %	
		1 mL L to 5 x 10 ⁶ L	
Gas Flow Rate Mass per Unit Time	0.5 mg/min to 5 kg/min	0.23 %	Gravimetric Method Electronic Balance
	0.5 mg/min to 5 kg/min	0.35 %	
Gas Flow Rate Volume per Unit Time	0.5 mL/min to 5000 L/min	0.28 %	Gravimetric Method Electronic Balance
	0.5 mL/min to 5000 L/min	0.35 %	
Torque Wrenches	2.5 N m to 25 N m	0.075 N m	Direct Method Transducer
	25 N m to 160 N m	0.48 N m	
	160 N m to 1000 N m	3 N m	

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Torque Analyzers and Torque Transducers	0.3 N m to 10 N m 10 N m to 100 N m 100 N m to 1000 N m	0.006 N m 0.04 N m 0.14 N m	Direct Method Balance Arms, Wheel, Mass sets.
Vibration Transducer, Vibration Meter	0.1 m/s ² to 98 m/s ² (10 Hz to 10 kHz)	1 %	Direct Method Portable Accelerometer Calibrator
Thermal			
PRT	-80 °C to 660 °C	0.01 °C	Comparison Method Precision Thermometry Bridge with RTD
Thermocouples (J,K,R,S,T,B)	0 °C to 1000 °C	0.5 °C	Comparison Method Thermocouple and Digital Multimeter or Digital Thermometer
Temperature Sensors with Readout (J, K, T, R, S, B or RTD or Thermistor)	-80 °C to 600 °C	0.03 °C	Comparison Method Digital Thermometer
Ovens and Furnaces	Up to 300 °C	1.5 °C	Comparison Method Digital Thermometer with 12 T-type TCs
Infrared Thermometers	-30 °C to 100 °C 100 °C to 500 °C	0.4 % 0.3 %	Comparison Method IR Calibrator, Digital Thermometer and RTD or Thermocouple
Liquid in Glass Thermometer	-30 °C to 250 °C	0.07 °C	Comparison Method Digital Thermometer
Humidity Meters, Humidity Data Loggers	25 %RH to 90 %RH (15 °C to 50 °C) 1 °C to 60 °C (50 % RH)	0.61 %RH 0.3 °C	Comparison Method General Eastern Hygrometer, Humidity Chamber
Humidity Measure ⁴	5 %RH to 95 %RH (5 °C to 100 °C)	0.39 %RH	Comparison Method General Eastern Hygrometer
Electrical – DC/LF			
DC Voltage – Generate ³	1 V 10 V	3.6 µV/V 1.0 µV/V	Fluke 732A Direct method
	32.9 mV to 329.9 mV 329.9 mV to 3.29 V 3.29 V to 32.9 V 32.9 V to 329.9 V	0.015 % to 70 µV/V 70 µV/V to 52 µV/V 52 µV/V to 53 µV/V 53 µV/V to 58 µV/V	Fluke 5500A Direct method

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	100 V to 1020 V	71 μ V/V to 58 μ V/V	
DC Voltage – Measure ⁴	10 mV to 100 mV 100 mV to 1 V 1 V to 10 V 10 V to 100 V 100 V to 1000 V	12 μ V/V 12 μ V/V to 8.4 μ V/V 8.4 μ V/V to 8.1 μ V/V 8.1 μ V/V to 10 μ V/V 10 μ V/V to 11 μ V/V	HP 3458A Direct method
DC Current – Generate ³	0.33 mA to 3.29 mA 3.29 mA to 32.9 mA 32.9 mA to 329.9 mA 329.9 mA to 2.19 A 2.19 A to 11 A	0.028 % to 0.015 % 0.015 % to 0.012 % 0.012 % to 0.018 % 0.018 % to 0.036 % 0.036 % to 0.064 %	Fluke 5500A Direct method
	10 A to 1000 A	0.51 % to 0.17 %	Fluke 5500A with 100-turn coil Direct method
DC Current – Measure ⁴	100 nA to 1 μ A 1 μ A to 10 μ A 10 μ A to 100 μ A 100 μ A to 1 mA 1 mA to 10 mA 10 mA to 100 mA 100 mA to 1 A	0.043 % to 62 μ A/A 62 μ V/V to 32 μ A/A 32 μ V/V to 29 μ A/A 29 μ V/V to 26 μ A/A 26 μ A/A 26 μ V/V to 41 μ A/A 41 μ A/A to 0.012 %	HP 3458A Direct method
	1 A to 100 A	0.015 %	HP 3458A Shunt Indirect Method
AC Current Generate ³	0.033 mA (50 Hz) (1 kHz) (5 kHz)	0.20 % 0.20 % 0.45 %	Fluke 5500A Direct method
	0.329 mA (50 Hz) (1 kHz) (5 kHz)	0.0046 % 0.0046 % 0.0046 %	
	3.29 mA (50 Hz) (1 kHz) (5 kHz)	0.11 % 0.11 % 0.21 %	
	32.9 mA (50 Hz) (1 kHz) (5 kHz)	0.099 % 0.099 % 0.21 %	



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AC Current Generate ³ (continued)	329.9 mA (50 Hz) (1 kHz) (5 kHz)	0.10 % 0.10 % 0.21 %	Fluke 5500A Direct method
	2.19 A (50 Hz) (1 kHz) (5 kHz)	0.11 % 0.11 % 0.77 %	
	11 A (50 Hz) (1 kHz)	0.12 % 0.35 %	
	700 A (50 Hz) (1 kHz)	0.10 % 0.33 %	Fluke 5500A with 100-turn coil Direct method
AC Current – Measure ⁴	10 µA (50 Hz) (1 kHz) (10 kHz)	0.45 % 0.36 % 0.36 %	HP 3458A Direct method
	100 µA (50 Hz) (1 kHz) (10 kHz)	0.18 % 0.090 % 0.090 %	
	1 mA (50 Hz) (1 kHz) (10 kHz)	0.090 % 0.050 % 0.080 %	
	10 mA (50 Hz) (1 kHz) (10 kHz)	0.080 % 0.050 % 0.080 %	
	100 mA (50 Hz) (1 kHz) (10 kHz)	0.080 % 0.050 % 0.080 %	
	1 A (50 Hz) (1 kHz) (10 kHz)	0.10 % 0.12 % 0.32 %	

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AC Voltage Generate ³	3.29 mV (50 Hz to 10 kHz)	0.76 %	Fluke 5500A Direct method
	(50 kHz)	0.86 %	
	(100 kHz)	1.4 %	
	32.9 mV (50 Hz to 10 kHz)	0.21 %	
	(50 kHz)	0.31 %	
	(100 kHz)	0.45 %	
	329.9 mV (50 Hz to 10 kHz)	0.056 %	
	(50 kHz)	0.17 %	
	(100 kHz)	0.29 %	
	3.29 V (50 Hz to 10 kHz)	0.32 %	
	(50 kHz)	0.15 %	
	(100 kHz)	0.29 %	
	32.9 V (50 Hz to 10 kHz)	0.42 %	
	(50 kHz)	0.21 %	
(100 kHz)	0.29 %		
329.9 V (50 Hz to 1 kHz)	0.055 %	HP 3458A Direct method	
(10 kHz)	0.088 %		
(50 kHz)	0.099 %		
1020 V (50 Hz to 1 kHz)	0.055 %		
(10 kHz)	0.22 %		
(50 kHz)	0.22 %		
1 mV (50 Hz to 10 kHz)	0.14 %		
(50 kHz)	0.21 %		
(100 kHz)	0.61 %		
10 mV (50 Hz to 10 kHz)	0.041 %		
(50 kHz)	0.11 %		
(100 kHz)	0.51 %		

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AC Voltage Measure ⁴ (continued)	100 mV (50 Hz to 10 kHz)	0.016 %	HP 3458A Direct method	
	(50 kHz)	0.032 %		
	(100 kHz)	0.082 %		
	1 V (50 Hz to 10 kHz)	0.016 %		
	(50 kHz)	0.032 %		
	(100 kHz)	0.082 %		
10 V (50 Hz to 10 kHz)	(50 kHz)	0.032 %		
	(100 kHz)	0.082 %		
	100 V (50 Hz to 10 kHz)	0.016 %		
	(50 kHz)	0.032 %		
	(100 kHz)	0.014 %		
	1000 V (50 Hz to 10 kHz)	0.022 %		
(50 kHz)	0.037 %			
(100 kHz)	0.014 %			
DC Resistance –Generate ³	1 Ω	9.0 μΩ/Ω	Resistances Standard Direct method	
	10 Ω	9.5 μΩ/Ω		
	1 kΩ	9.5 μΩ/Ω		
	10 kΩ	35 μΩ/Ω		
	0.01 Ω to 0.1 Ω	0.050 %	Decade Resistors Direct method	
	0.1 Ω to 1 Ω	0.020 %		
	1 Ω to 10.9 Ω	0.075 %	Fluke 5500A Direct method	
	10.9 Ω to 32.9 Ω	0.075 % to 0.047 %		
	32.9 Ω to 109.9 Ω	0.047 % to 0.023 %		
	109.9 Ω to 329.9 Ω	0.023 % to 0.014 %		
	329.9 Ω to 1.09 kΩ	0.014 % to 0.015 %		
	1.09 kΩ to 3.29 kΩ	0.015 % to 0.011 %		
	3.29 kΩ to 10.9 kΩ	0.011 % to 0.015 %		
	10.9 kΩ to 32.9 kΩ	0.015 % to 0.011 %		
	32.9 kΩ to 109.9 kΩ	0.011 % to 0.017 %		
	109.9 kΩ to 329.9 kΩ	0.017 % to 0.014 %		
	329.9 kΩ to 1.09 MΩ	0.014 % to 0.024 %		
	1.09 MΩ to 3.29 MΩ	0.024 % to 0.019 %		
	3.29 MΩ to 10.9 MΩ	0.019 % to 0.088 %		
	10.9 MΩ to 32.9 MΩ	0.088 % to 0.12 %		
32.9 MΩ to 109.9 MΩ	0.12 % to 0.72 %			
109.9 MΩ to 330 MΩ	0.72 %			



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DC Resistance –Generate ³ (continued)	100 MΩ to 200 MΩ	0.12 % to 0.60 %	Decade Resistors Direct method	
	200 MΩ to 300 MΩ	0.60 % to 0.59 %		
	300 MΩ to 1 GΩ	0.59 %	HP 3458A Replacement method	
	1 Ω to 10 Ω	87 μΩ/Ω to 21 μΩ/Ω		
	10 Ω to 100 Ω	21 μΩ/Ω to 17 μΩ/Ω		
	100 Ω to 1 kΩ	17 μΩ/Ω to 11 μΩ/Ω		
	1 kΩ to 10 kΩ	11 μΩ/Ω		
	10 kΩ to 100 kΩ	11 μΩ/Ω		
	100 kΩ to 1 MΩ	11 μΩ/Ω to 19 μΩ/Ω		
	1 MΩ to 10 MΩ	19 μΩ/Ω to 61 μΩ/Ω		
DC Resistance –Measure ⁴	0.01 Ω to 0.1 Ω	0.080 %	Fluke 5500A HP 3458A Indirect Method	
	0.1 Ω to 1 Ω	0.080 %		
	1 Ω to 10 Ω	66 μΩ/Ω to 20 μΩ/Ω	HP 3458A Direct method	
	10 Ω to 100 Ω	20 μΩ/Ω to 17 μΩ/Ω		
	100 Ω to 1 kΩ	17 μΩ/Ω to 11 μΩ/Ω		
	1 kΩ to 10 kΩ	11 μΩ/Ω		
	10 kΩ to 100 kΩ	11 μΩ/Ω		
	100 kΩ to 1 MΩ	11 μΩ/Ω to 19 μΩ/Ω		
	1 MΩ to 10 MΩ	19 μΩ/Ω to 61 μΩ/Ω		
	10 MΩ to 100 MΩ	61 μΩ/Ω to 0.51 %		
	100 MΩ to 1 GΩ	0.51 % to 0.5 %	Resistances Standard Potentiometric method	
	1 Ω	8.1 μΩ/Ω		
	10 Ω	8.1 μΩ/Ω		
	1 kΩ	7.3 μΩ/Ω		
	10 kΩ	34 μΩ/Ω		
Time and Frequency				
Frequency – Measure ⁴ (Sine, Square, Pulse Signal)	In laboratory: 1 mHz to 10 Hz	1.5 x 10 ⁻⁵	Direct method Primary time base plus universal counter	
	At customer site: 1 mHz to 10 Hz	2.5 x 10 ⁻⁵		
	In laboratory: 10 Hz to 1 kHz 1 kHz to 1 MHz 1 MHz to 200 MHz 200 MHz to 500 MHz	10 Hz to 1 kHz	1.9 x 10 ⁻⁹	Direct method Primary time base plus universal counter
		1 kHz to 1 MHz	4.3 x 10 ⁻¹⁰	
1 MHz to 200 MHz		1.9 x 10 ⁻¹¹		
200 MHz to 500 MHz		3.7 x 10 ⁻¹¹		
At customer site: 10 Hz to 1 kHz 1 kHz to 1 MHz	10 Hz to 1 kHz	3.7 x 10 ⁻⁷	Direct method Primary time base plus universal counter	
	1 kHz to 1 MHz	3.0 x 10 ⁻⁸		



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	1 MHz to 200 MHz 200 MHz to 500 MHz	3.0×10^{-8} 2.0×10^{-9}	
Frequency – Generate ³ (Pulse, Sinusoidal, Square Signal)	In laboratory: 1 mHz to 500 MHz	4.3×10^{-11}	Direct method Primary time base + function generator
	At customer site: 1 mHz to 500 MHz	3.0×10^{-10}	Direct method Primary time base + function generator
Period – Measure ⁴ (Pulse, Sinusoidal, Square Signal)	In laboratory: 1 ns to 1 ms 1 ms to 1 s 1 s to 1000 s	4.7×10^{-11} 3.0×10^{-7} 3.0×10^{-4}	Direct method Primary time base + universal counter
	At customer site: 1 ns to 1 ms 1 ms to 1 s 1 s to 1000 s	2.0×10^{-9} 3.0×10^{-7} 3.0×10^{-4}	Direct method Primary time base + universal counter
Period – Generate ³ (Pulse, Sinusoidal, Square Signal)	In laboratory: 1 ns to 1000 s	4.3×10^{-11}	Direct method Primary time base + function generator or time mark generator
	At customer site: 1 ns to 1000 s	3.0×10^{-10}	Direct method Primary time base + function generator or time mark generator
Time Interval – Measure ⁴	In laboratory: 1.25 ns to 86400 s	4.7×10^{-11}	Direct method Primary time base + universal counter
	At customer site: 1.25 ns to 86400 s	3.0×10^{-10}	Direct method Primary time base + universal counter
Time Interval – Generate ³	In laboratory: 1.25 ns to 86400 s	4.3×10^{-11}	Direct method Primary time base + universal counter
	At customer site: 1.25 ns to 86400 s	3.0×10^{-10}	Direct method Primary time base + universal counter
Timers – Measure ⁴	At customer site: 10 ms to 86400 s	0.58 ms	Direct method Chronometer
Bandwidth – Generate ³	DC to 26 GHz	0.18 dB	Direct method Primary time base + synthesized signal generator



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<i>RF/Microwave and Electromagnetics</i>			
Frequency – Measure ⁴ (Pulse, Square or Sinusoidal Signal)	In laboratory: 500 MHz to 18 GHz	4.7 x 10 ⁻¹¹	Direct method Primary time base + universal counter
	At customer site: 500 MHz to 18 GHz	2.0 x 10 ⁻⁹	
Frequency – Generate ³ (Pulse, Square or Sinusoidal Signal)	In laboratory: 500 MHz to 18 GHz	4.3 x 10 ⁻¹¹	Direct method Primary time base + universal counter
	At customer site: 500 MHz to 18 GHz	3.0 x 10 ⁻¹⁰	

¹The uncertainty covered by the Calibration and Measurement Capability (CMC) is expressed as the expanded uncertainty having a coverage probability of approximately 95 %. It is the smallest measurement uncertainty that a laboratory can achieve within its scope of accreditation when performing calibrations of a best existing device. The measurement uncertainty reported on a calibration certificate may be greater than that provided in the CMC due to the behavior of the calibration item and other factors that may contribute to the uncertainty of a specific calibration.

²When uncertainty is stated in relative terms (such as percent, a multiplier expressed as a decimal fraction or in scientific notation), it is in relation to instrument reading or instrument output, as appropriate, unless otherwise indicated.

³Capability is suitable for the calibration of measuring devices in the stated ranges.

⁴Capability is suitable for the calibration of devices intended to generate the indicated quantity in the stated ranges.

